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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of:
Tidrow, et al

Docket No.: ARL 00-25

Serial No.: 10/087,766

Art Unit:

Filed: 03/05/02

Examiner:

For: Apparatus for Precision Measurement of
Microwave Material Properties
As Functions of Temperature and Frequency

Commissioner of Patents and Trademarks Office

Washington, D.C. 20231

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INFORMATION DISCLOSURE STATEMENT

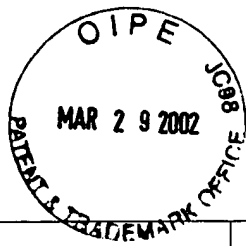
In accordance with 37 CFR §§1.56, 1.97 and 1.98 applicants hereby call to the attention of the Examiner the references cited on the PTO-1449, attached hereto.

These citations do not constitute an admission that the references are relevant or material to the claims. They are cited only as constituting the closest art of which the Applicants are aware.

Respectfully submitted,

29 MARCH 2002

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PTO Form 1449 INFORMATION DISCLOSURE STATEMENT BY APPLICANT				APPLICATION NUMBER		10/087,766			
				FILING DATE		03/05/02			
				FIRST NAMED INVENTOR		Tidrow, et al			
				GROUP ART UNIT					
				EXAMINER NAME					
SHEET	1	OF	1	ATTORNEY DOCKET NUMBER				ARL 00-25	
Examiner initials	U.S. Patent Number	Name of Patentee or Applicant of Cited Document			Patent Date	Class	Subclass	Filing Date if Known	
FOREIGN PATENT DOCUMENTS									
OTHER INFORMATION (including author, title, date, pertinent pages, etc.)									
1A	"The Accurate Measurement of Permittivity by Means of an Open Resonator," A.L. Cullen and P.K. Yr, Proc. R. Soc. Lond. A. 325, 493-509 (1971)								
EXAMINER:					DATE CONSIDERED:				
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609, draw line through citation if not in conformance and not considered, include copy of this form with next communication to applicant									

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